



PATENT APPLICATION

Sheet 1 of 2

FORM PTO-1449

LIST OF PATENTS AND PUBLICATIONS FOR
APPLICANT'S INFORMATION DISCLOSURE
STATEMENT

(Use several sheets if necessary)

ATTY. DOCKET NO. 200312936-1	APPLICATION NO. 10/606,715	CONFIRMATION NO. 5780
APPLICANT Benjamin T. Percer et al.		
FILING DATE 06-26-2003	GROUP 2863	

REFERENCE DESIGNATION

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	PUBLICATION DATE	NAME	Pages, Columns, Lines Where Relevant Passages or Figures Appear
FL	1A	5,157,326	Oct. 20, 1992	BURNSIDES	_____
	1B	6,476,615	Nov. 05, 2002	MARBOT ET AL.	_____
	1C	6,563,350	May 13, 2003	WARNER ET AL.	_____
	1D	6,564,350	May 13, 2003	HOEWELER	_____
	1E	6,697,952	Feb. 24, 2004	KING	_____
	1F				
	1G				
	1H				
	1I				
	1J				
	1K				

FOREIGN PATENT DOCUMENTS

		COUNTRY DOCUMENT NUMBER	PUBLICATION DATE	NAME OF PATENTEE OR APPLICANT	Pages/Columns/Lines Where Relevant Passages/Figures Appear	Check if Translation attached
FL	1L	JP/62-262165	11-14-1987	NIPPON ELECTRIC	_____	
FL	1M	EP/0 505 120	09-23-1992	AMDAHL	_____	
FL	1N	JP/5-2502	01-08-1993	NIPPON ELECTRIC	_____	
FL	1O	GB/1 219 001	01-13-1971	INDUSTRIAL NUCLEONIC	_____	
	1P					

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)

FL	1Q	Great Britain Search Report. Application No. GB0413503.4. October 27, 2004.
FL	1R	Great Britatin Search Report. Application No. GB0413502.6. November 9, 2004.
FL	1S	Great Britain Search Report. Application No. GB 0413501.8. November 5, 2004.

EXAMINER

John Se

DATE CONSIDERED

05/05/2005



PATENT APPLICATION
Sheet 2 of 2

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APPLICANT'S INFORMATION DISCLOSURE
STATEMENT

(Use several sheets if necessary)

ATTY. DOCKET NO.

200208051-1

APPLICATION NO.

10/600,463

CONFIRMATION NO.

APPLICANT

Benjamin T. Percer et al.

FILING DATE

06-26-2003

GROUP

2863

REFERENCE DESIGNATION

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	PUBLICATION DATE	NAME	Pages, Columns, Lines Where Relevant Passages or Figures Appear
	2A			
	2B			
	2C			
	2D			
	2E			
	2F			
	2G			
	2H			
	2I			
	2J			
	2K			

FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	PUBLICATION DATE	NAME OF PATENTEE OR APPLICANT	Pages/Columns/Lines Where Relevant Passages/Figures Appear	Check if Translation attached
	2L				
	2M				
	2N				
	2O				
	2P				

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)

2Q	Berner, et al. "DC Voltage Margin Tester. NB84092465. IBM Technical Disclosure Bulletin, Vol. 27, No. 4B, September 1984, pg. 246.
2R	Tsukude, et al. "Highly Reliable Testing of ULSI Memories with On-Chip Voltage-Down Converters". IEEE Design & Test Computers. June 1993, pgs. 6-12.
2S	

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05/05/2005